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Part 4-23: Testing and measurement techniques – Test methods for protective devices for HEMP and other radiated disturbances

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

Electromagnetic compatibility (EMC) - Part 4-23: Testing and measurement techniques - Test methods for protective devices for HEMP and other radiated disturbances

FOREWORD

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This consolidated version of the official IEC Standard and its amendment has been prepared for user convenience.

IEC 61000-4-23 edition 2.1 contains the second edition (2016-10) [documents 77C/253/CDV and 77C/257/RVC] and its amendment 1 (2025-07) [documents 77C/351/FDIS and 77C/353/RVD].

In this Redline version, a vertical line in the margin shows where the technical content is modified by amendment 1. Additions are in green text, deletions are in strikethrough red text. A separate Final version with all changes accepted is available in this publication.

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International Standard IEC 61000-4-23 has been prepared by subcommittee 77C: High power transient phenomena, of IEC technical committee 77: Electromagnetic compatibility.

It forms Part 4-23 of IEC 61000. It has the status of a basic EMC publication in accordance with IEC Guide 107.

This second edition cancels and replaces the first edition published in 2000. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

a) updates to the shielding effectiveness (SE) test method in Clause 5;
b) a new Annex F describing methods for testing ‘inside-to-out’ has been added.

The text of this standard is based on the following documents:

CDV	Report on voting
77C/253/CDV	77C/257/RVC

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 61000 series, published under the general title *Electromagnetic compatibility (EMC)*, can be found on the IEC website.

The committee has decided that the contents of this document and its amendment will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn, or
- revised.

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INTRODUCTION

IEC 61000 is published in separate parts, according to the following structure:

Part 1: General

General considerations (introduction, fundamental principles)
Definitions, terminology

Part 2: Environment

Description of the environment
Classification of the environment
Compatibility levels

Part 3: Limits

Emission limits
Immunity limits (in so far as they do not fall under the responsibility of the product committees)

Part 4: Testing and measurement techniques

Measurement techniques
Testing techniques

Part 5: Installation and mitigation guidelines

Installation guidelines
Mitigation methods and devices

Part 6: Generic Standards

Part 9: Miscellaneous

Each part is further subdivided into several parts, published either as international standards, as technical specifications or technical reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and a second number identifying the subdivision (example: IEC 61000-6-1).

The IEC has initiated the preparation of standardized methods to protect civilian society from the effects of high power electromagnetic (HPEM) environments. Such effects could disrupt systems for communications, electric power, information technology, etc.

This part of IEC 61000 is an international standard that establishes the test concepts, set-ups, required equipment, and test procedures for protective devices against HEMP radiated disturbances.

Annex F provides examples of the SE test method placing the TX antenna inside the barrier.

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1 Scope

This part of IEC 61000 provides a protective devices test method for HEMP and other radiated disturbances. It is primarily intended for HEMP testing but can be applied to other externally generated radiated disturbances where appropriate. It provides a brief description of the most important concepts for testing of shielding elements. For each test, the following basic information is provided:

– theoretical foundation of the test (the test concepts);
– test set-up including outside-to-in and inside-to-out measurements;
– required equipment;
– test procedures;
– data processing.

This international standard does not provide information on requirements for specific levels for testing.

This part of IEC 61000 has been updated to include a new test method.

Due to the available space, a transmitting antenna position outside the barrier has mainly been suggested. However, nowadays, many EMP protection facilities in practical use do not actually have enough space available outside the electromagnetic barrier due to physical constraints such as concrete walls or soil to allow the method described in IEC 61000-4-23:2000 (edition 1) to be applied correctly. From experience many facilities have available space for a 1 m separation or less only.

Therefore, in many practical cases it is not possible to measure shielding effectiveness according to the test method of previous documents. The constructors for EMP protection facilities are also unwilling to build facilities with extra space for measurements with the transmitting antenna outside the barrier due to the great expense and inefficiency of the operational working area for new or existing buildings.

This document provides additionally a method that allows the transmitting antenna to be placed inside the enclosure and the receiving antenna outside the barrier (‘inside-to-out’ method). Annex F includes test set-up and procedure examples.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-161, *International Electrotechnical Vocabulary (IEV) – Part 161: Electromagnetic compatibility* (available at www.electropedia.org)

IEC 61000-2-9, *Electromagnetic compatibility (EMC) – Part 2: Environment – Section 9: Description of HEMP environment – Radiated disturbance*

IEC 61000-5-3, *Electromagnetic compatibility (EMC) – Part 5-3: Installation and mitigation guidelines – HEMP protection concepts*